IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Prior Application: M. SAKAIRI et al

Serial No. 09/987,094 Filed: November 13, 2001

Group Art:

1743

Examiner:

A. Soderquist

For:

CHEMICAL MONITORING METHOD AND APPARATUS,

AND INCINERATOR

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

March 10, 2004

Sir:

In accordance with the duty of disclosure, the applicants inform the Examiner of the documents cited during prosecution of the parent application, USSN 09/987,094 and related application USSN No. 10/119,844, filed April 11, 2002.

The applicants request the Examiner to initial and return a copy of the attached PTO-1449 form as an indication that the documents have been considered.

Respectfully submitted,

Daniel J. Stanger

Registration No. 32,846
Attorney for Applicant(s)

MATTINGLY, STANGER & MALUR, P.C. 1800 Diagonal Road, Suite 370 Alexandria, Virginia 22314 Telephone: (703) 684-1120 Facsimile: (703) 684-1157

Date: March 10, 2004

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	AF	5,0	36,195	07/1991	Batey et al					
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		Int. Sy	mp. 5th, 19	81, pp. 179-	188.			
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	AS _	J.F. Vi	card et al,	Fresenius"	J. Anal Chem., 19	94, 348, p	p. 101-105	5.	
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	AS	A. Berg	man et al,	Chemosphere	, 1995, 30, pp.	1921-193	8.			
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